

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1896	SERIAL NO. 10/050,373
		LIST OF ARTS SEARCHED BY APPLICANT (Use several sheets if necessary)		APPLICANT: Gurtej S. Sandhu, et al.	
				FILING DATE January 15, 2002	GROUP 2813

U.S. PATENT DOCUMENTS

*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
Xle	AA	3,627,598	12/1971	McDonald, et al.			
Xle	AB	4,254,161	03/1981	Kemlage			
Xle	AC	4,262,631	04/1981	Kubacki			
Xle	AD	4,435,447	03/1984	Ito, et al.			
Xle	AE	4,882,649	11/1989	Chen, et al.			
Xle	AF	4,891,684	01/1990	Nishioka, et al			
Xle	AG	4,980,307	12/1990	Ito, et al.			
Xle	AH	4,996,081	02/1991	Ellul, et al.			
Xle	AI	5,051,794	09/1991	Mori			

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
Xle	EP 0886308 A2	12/1998	Europe				
Xle	237243 a	04/2001	Japan (ASM America, Inc.)				

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

Xle	AM	Wolf, Stanley, "Silicon Processing for the VLSI Era, Volume 3: The Submicron Mosfet", Lattice Press, 1995, pages 648-9.
		Laughery, et al, "Effect of H ₂ Content on Reliability of Ultrathin In-Situ Steam Generated (ISSG) SiO ₂ , EEE Electron Device Letters, September, 2000, Volume 21, No. 9.
	AN	
	AO	

EXAMINER

DATE CONSIDERED

11/05/05

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Form PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					ATTY. DOCKET NO. MI22-1896		SERIAL NO. 10/050,373	
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U.S. PATENT DOCUMENTS								
*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>GLE</i>	AA	5,142,438	08/1992	Reinberg, et al.				
<i>GLE</i>	AB	5,227,651	07/1993	Kim, et al.				
<i>GLE</i>	AC	5,237,188	08/1993	Iwai, et al.				
<i>GLE</i>	AD	5,324,679	06/1994	Kim, et al.				
<i>GLE</i>	AE	5,330,936	07/1994	Ishitanti				
<i>GLE</i>	AF	5,350,707	09/1994	Ko, et al.				
<i>GLE</i>	AG	5,376,593	12/1994	Sandhu, et al.				
<i>GLE</i>	AH	5,393,702	02/1995	Yang, et al.				
<i>GLE</i>	AI	5,397,748	03/1995	Watanabe, et al.				
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
	AJ						Yes	No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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EXAMINER <i>newer Sectley</i>		DATE CONSIDERED <i>1/25/05</i>						
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U.S. TRADE DOCUMENTS

*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>Xue</i>	AA	5,398,641	03/1995	Shih			
	AB	5,459,105	10/1995	Matsuura			
	AC	5,498,890	03/1996	Kim, et al.			
	AD	5,504,029	04/1996	Murata, et al.			
	AE	5,508,542	04/1996	Geiss, et al.			
	AF	5,523,596	06/1996	Ohi, et al.			
	AG	5,731,235	03/1998	Srinivasan, et al.			
<i>Xue</i>	AH	5,821,142	10/1998	Sung, et al.			
<i>Xue</i>	AI	5,844,771	12/1998	Graettinger, et al.			

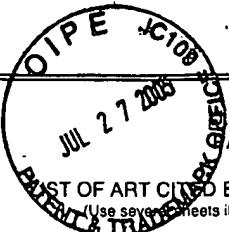
FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation
							Yes
	AJ						No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

<i>Honey S. Sandhu</i>	AM		
	AN		
	AO		
EXAMINER	DATE CONSIDERED	<i>11/05/05</i>	

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*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>Jle</i>	AA	5,851,603	12/1998	Tsai, et al.				
	AB	5,882,978	03/1999	Srinivasan, et al.				
	AC	6,001,741	12/1999	Alers				
	AD	6,001,748	12/1999	Tanaka				
	AE	6,008,104	12/1999	Schrems				
	AF	6,051,865	04/2000	Gardner, et al.				
	AG	6,063,713	06/2000	Doan				
	AH	6,077,754	06/2000	Srinivasan, et al.				
<i>Jle</i>	AI	6,090,597	08/2000	Tsu, et al.				
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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EXAMINER <i>Gurtej S. Sandhu</i>		DATE CONSIDERED <i>11/25/05</i>						
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*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>elle</i>	AA	6,111,744	08/2000	Doan			
	AB	6,168,980	01/2001	Yamazaki, et al.			
	AC	6,207,985 B1	03/2001	Walker			
	AD	6,323,138 B1	11/2001	Doan			
	AE	6,348,420 B1	02/2002	Raaijmakers, et al.			
	AF	6,265,327	07/2001	Kobayashi, et al.			
	AG	6,350,707 B1	02/2002	Liu, et al.			
<i>V</i>	AH	6,723,599 B2	04/2004	Eppich, et al.			
<i>elle</i>	AI	6,893,981 B2	05/2005	Park, et al.			

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AK							
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

<i>elle</i>	AM							
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Xle	AA	09/653,281	08/2000	Beaman, et al.				
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	AC							
	AD							
	AE							
	AF							
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	AI							
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	AK							No
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	AN							
	AO							
EXAMINER	<i>harris Schley</i>	DATE CONSIDERED	<i>11/25/05</i>					
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<i>Xle</i>	AA	2001/0036752	11/2001	DeBoer, et al.				
	AB	2002/0009861	08/1998	Narwankar, et al.				
	AC	2002/0052124	05/2002	Raaijmakers, et al.				
<i>Xle</i>	AD	2003/0034518A1	02/2003	Yoshikawa				
	AE							
	AF							
	AG							
	AH							
	AI							
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